

MOS FIELD EFFECT TRANSISTOR 2SK3576

N-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The 2SK3576 is a switching device which can be driven directly by a 2.5 V power source.

The device features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

- 2.5V drive available
- · Low on-state resistance

RDS(on)1 = 50 m Ω MAX. (VGS = 4.5 V, ID = 2.0 A)

 $R_{DS(on)2} = 53 \text{ m}\Omega$ MAX. (Vgs = 4.0 V, ID = 2.0 A)

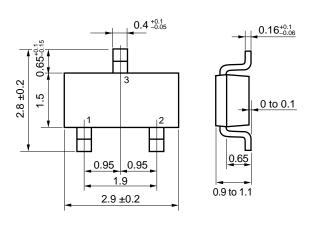
 $R_{DS(on)3} = 75 \text{ m}\Omega \text{ MAX.} (V_{GS} = 2.5 \text{ V}, I_{D} = 2.0 \text{ A})$

ORDERING INFORMATION

PART NUMBER	PACKAGE
2SK3576	SC-96 (Mini Mold Thin Type)

Marking: XK

PACKAGE DRAWING (Unit: mm)

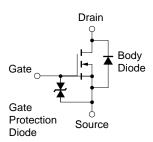


1: Gate 2: Source 3: Drain

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	20	V
Gate to Source Voltage (Vps = 0 V)	Vgss	±12	V
Drain Current (DC) (T _A = 25°C)	I _{D(DC)}	±4.0	Α
Drain Current (pulse) Note1	D(pulse)	±16	Α
Total Power Dissipation (T _A = 25°C)	P _{T1}	0.2	W
Total Power Dissipation (T _A = 25°C) Note2	P _{T2}	1.25	W
Channel Temperature	Tch	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

EQUIVALENT CIRCUIT



Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

2. Mounted on FR-4 board, $t \le 5$ sec.

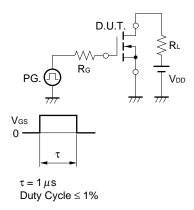
Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

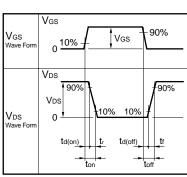
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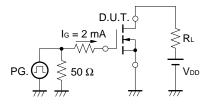
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	Ipss	V _{DS} = 20 V, V _{GS} = 0 V			10	μΑ
Gate Leakage Current	Igss	$V_{GS} = \pm 12 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1.0 mA	0.5		1.5	V
Forward Transfer Admittance	yfs	V _{DS} = 10 V, I _D = 2.0 A	1.0			S
Drain to Source On-state Resistance	RDS(on)1	V _G S = 4.5 V, I _D = 2.0 A		40	50	mΩ
	RDS(on)2	Vgs = 4.0 V, ID = 2.0 A		42	53	mΩ
	RDS(on)3	Vgs = 2.5 V, ID = 2.0 A		56	75	mΩ
Input Capacitance	Ciss	V _{DS} = 10 V		250		pF
Output Capacitance	Coss	V _G S = 0 V		80		pF
Reverse Transfer Capacitance	Crss	f = 1.0 MHz		60		pF
Turn-on Delay Time	t d(on)	V _{DD} = 10 V, I _D = 2.0 A		28		ns
Rise Time	tr	V _G S = 4.0 V		140		ns
Turn-off Delay Time	td(off)	R _G = 10 Ω		110		ns
Fall Time	t f			180		ns
Total Gate Charge	Q _G	V _{DD} = 16 V		3.3		nC
Gate to Source Charge	Qgs	V _G S = 4.0 V		0.7		nC
Gate to Drain Charge	Q _{GD}	I _D = 4.0 A		1.5		nC
Body Diode Forward Voltage	V _{F(S-D)}	IF = 4.0 A, VGS = 0 V		0.89		V

TEST CIRCUIT 1 SWITCHING TIME



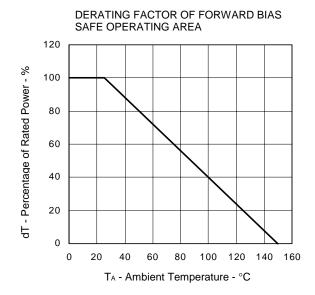


TEST CIRCUIT 2 GATE CHARGE



100 120 140 160

李河GAL CHARACTER ISTICS (TA = 25°C)



AMBIENT TEMPERATURE 1.5 N 1.25 O.75 O.25

0

0

20

40

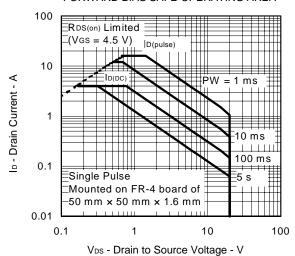
60

80

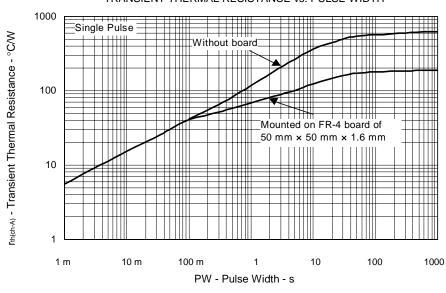
T_A - Ambient Temperature - °C

TOTAL POWER DISSIPATION vs.

FORWARD BIAS SAFE OPERATING AREA

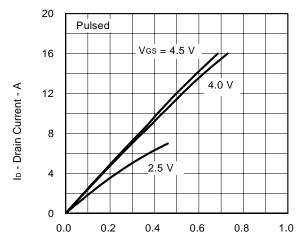


TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



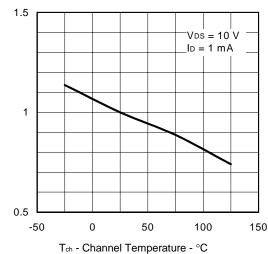
3

查询"2SK3576"(地際底CURRENT vs.

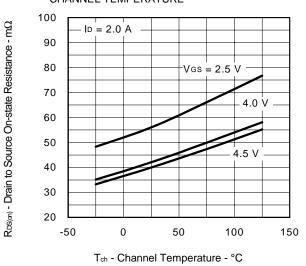


V_{DS} - Drain to Source Voltage - V

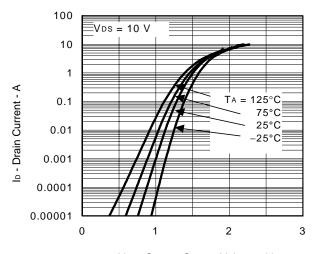
GATE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE



DRAIN TO SOURCE ON-STATERESISTANCE vs. CHANNEL TEMPERATURE

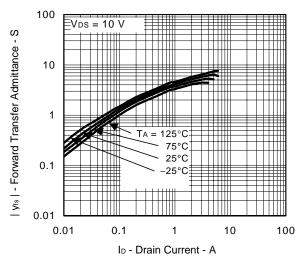


FORWARD TRANSFER CHARACTERISTICS

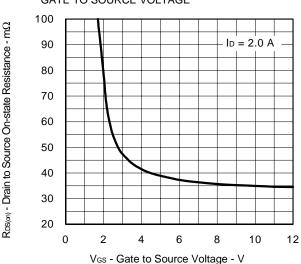


V_{GS} - Gate to Source Voltage - V

FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

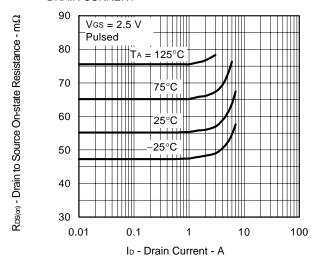


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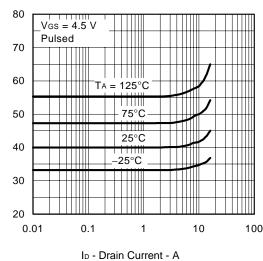
VGS(off) - Gate Cut-off Voltage - V

R_{DS(m)} - Drain to Source On-state Resistance - mΩ

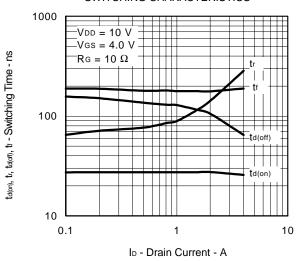
查询"2974%70"SOURCEON-STATE RESISTANCE vs.



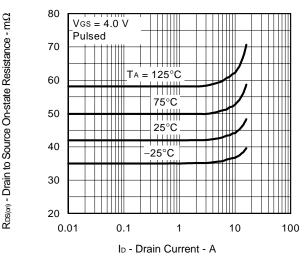
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



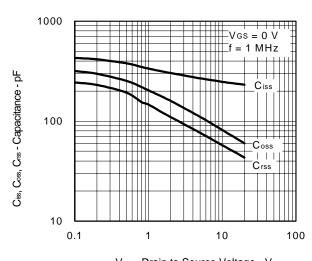
SWITCHING CHARACTERISTICS



DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT

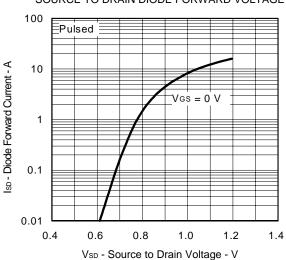


CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



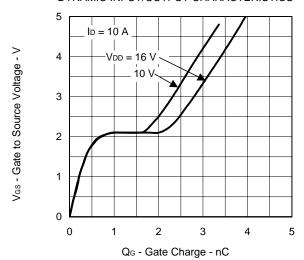
V_{DS} - Drain to Source Voltage - V

SOURCE TO DRAIN DIODE FORWARD VOLTAGE



查询"2SK3576"供应商

DYNAMIC INPUT/OUTPUT CHARACTERISTICS



查响》23K3576"供应商

查询"2SK3576"供应商

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